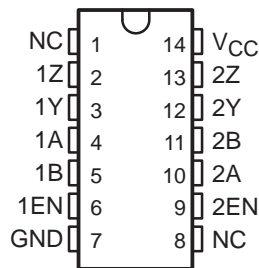


SN75159 DUAL DIFFERENTIAL LINE DRIVER WITH 3-STATE OUTPUTS

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- Meets or Exceeds the Requirements of ANSI EIA/TIA-422-B and ITU Recommendation V.11
- Single 5-V Supply
- Balanced Line Operation
- TTL Compatible
- High-Impedance Output State for Party-Line Applications
- High-Current Active-Pullup Outputs
- Short-Circuit Protection
- Dual Channels
- Clamp Diodes at Inputs

D OR N PACKAGE
(TOP VIEW)



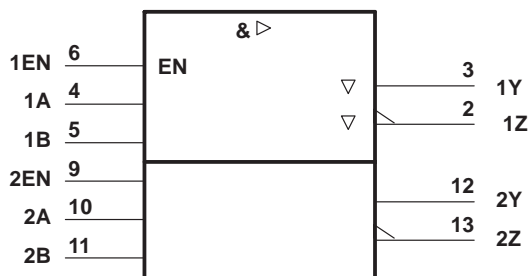
NC—No internal connection

description

The SN75159 dual differential line driver with 3-state outputs is designed to provide all the features of the SN75158 line driver with the added feature of driver output controls. There is an individual control for each driver. When the output control is low, the associated outputs are in a high-impedance state and the outputs can neither drive nor load the bus. This permits many devices to be connected together on the same transmission line for party-line applications.

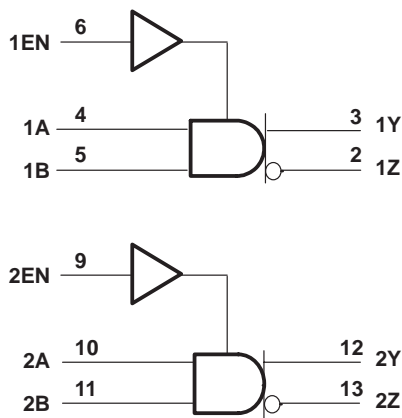
The SN75159 is characterized for operation from 0°C to 70°C.

logic symbol†



† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS
INSTRUMENTS**

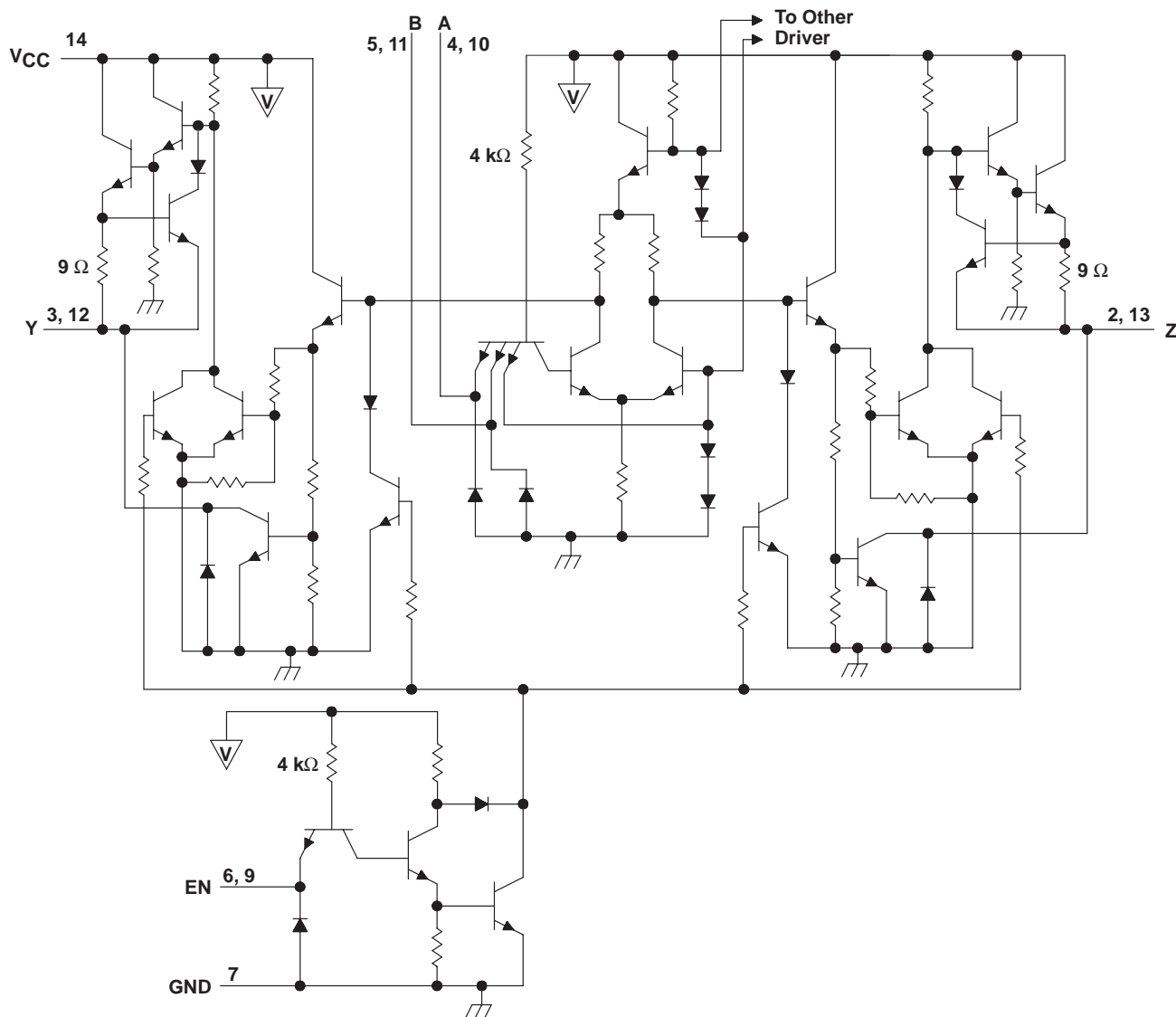
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schematic (each driver)



▽ ... VCC bus

Resistor values shown are nominal.

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage, V_I	5.5 V
Off-state voltage applied to open-collector outputs	12 V
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range, T_{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under “recommended operating conditions” is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values except differential output voltage V_{OD} are with respect to the network ground terminal. V_{OD} is at the Y output with respect to the Z output.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$ POWER RATING	DERATING FACTOR ABOVE $T_A = 25^\circ\text{C}$	$T_A = 70^\circ\text{C}$ POWER RATING
D	950 mW	7.6 mW/°C	608 mW
N	1150 mW	9.2 mW/°C	736 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}	4.75	5	5.25	V
High-level input voltage, V_{IH}	2			V
Low-level input voltage, V_{IL}			0.8	V
High-level output voltage, I_{OH}			–40	mA
Low-level output current, I_{OL}			40	mA
Operating free-air temperature, T_A	0		70	°C



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electrical characteristics over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP†	MAX	UNIT
V_{IK}	Input clamp voltage	$V_{CC} = 4.75 \text{ V}$,	$I_I = -12 \text{ mA}$		-0.9	-1.5	V
V_{OH}	High-level output voltage	$V_{CC} = 4.75 \text{ V}$, $V_{IH} = 2 \text{ V}$,	$V_{IL} = 0.8 \text{ V}$, $I_{OH} = -40 \text{ mA}$	2.4	3		V
V_{OL}	Low-level output voltage	$V_{CC} = 4.75 \text{ V}$, $V_{IH} = 2 \text{ V}$,	$V_{IL} = 0.8 \text{ V}$, $I_{OL} = 40 \text{ mA}$		0.25	0.4	V
V_{OK}	Output clamp voltage	$V_{CC} = 5.25 \text{ V}$,	$I_O = -40 \text{ mA}$		-1.1	-1.5	V
V_O	Output voltage	$V_{CC} = 4.75 \text{ V to } 5.25 \text{ V}$,	$I_O = 0$	0		6	V
$ V_{OD1} $	Differential output voltage	$V_{CC} = 5.25 \text{ V}$,	$I_O = 0$		3.5	$2V_{OD2}$	V
$ V_{OD2} $	Differential output voltage	$V_{CC} = 4.75 \text{ V}$		2	3		V
$\Delta V_{OD} $	Change in magnitude of differential output voltage‡	$V_{CC} = 4.75 \text{ V}$	$R_L = 100 \Omega$, See Figure 1		± 0.02	± 0.4	V
V_{OC}	Common-mode output voltage§	$V_{CC} = 5.25 \text{ V}$		1.8	3	V	
		$V_{CC} = 4.75 \text{ V}$		1.5	3		
$\Delta V_{OC} $	Change in magnitude of common-mode output voltage‡	$V_{CC} = 4.75 \text{ V to } 5.25 \text{ V}$		± 0.01	± 0.4	V	
I_O	Output current with power off	$V_{CC} = 0$	$V_O = 6 \text{ V}$	0.1	100	μA	
			$V_O = -0.25 \text{ V}$	-0.1	-100		
			$V_O = -0.25 \text{ V to } 6 \text{ V}$		± 100		
I_{OZ}	Off-state (high-impedance state) output current	$V_{CC} = 5.25 \text{ V}$, Output controls at 0.8 V	$T_A = 25^\circ\text{C}$	$V_O = 0 \text{ to } V_{CC}$	± 10	μA	
			$T_A = 70^\circ\text{C}$	$V_O = 0$	-20		
				$V_O = 0.4 \text{ V}$	± 20		
				$V_O = 2.4 \text{ V}$	± 20		
				$V_O = V_{CC}$	20		
I_I	Input current at maximum input voltage	$V_{CC} = 5.25 \text{ V}$,	$V_I = 5.5 \text{ V}$		1	mA	
I_{IH}	High-level input current	$V_{CC} = 5.25 \text{ V}$,	$V_I = 2.4 \text{ V}$		40	μA	
I_{IL}	Low-level input current	$V_{CC} = 5.25 \text{ V}$,	$V_I = 0.4 \text{ V}$	-1	-1.6	mA	
I_{OS}	Short-circuit output current¶	$V_{CC} = 5.25 \text{ V}$		-40	-90	-150	mA
I_{CC}	Supply current (both drivers)	$V_{CC} = 5.25 \text{ V}$, $T_A = 25^\circ\text{C}$,	Inputs grounded, No load		47	65	mA

† All typical values are at $V_{CC} = 5 \text{ V}$ and $T_A = 25^\circ\text{C}$ except for V_{OC} , for which V_{CC} is as stated under test conditions.

‡ $\Delta|V_{OD}|$ and $\Delta|V_{OC}|$ are the changes in magnitudes of V_{OD} and V_{OC} , respectively, that occur when the input is changed from a high level to a low level.

§ In ANSI Standard EIA/TIA-422-B, V_{OC} , which is the average of the two output voltages with respect to GND, is called output offset voltage, V_{OS} .

¶ Only one output should be shorted at a time, and duration of the short circuit should not exceed one second.

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switching characteristics over operating free-air temperature range, $V_{CC} = 5\text{ V}$

PARAMETER	TEST CONDITIONS	MIN	TYP†	MAX	UNIT
t _{PLH}	Propagation delay time, low-to-high-level output		16	25	ns
t _{PHL}	Propagation delay time, high-to-low-level output		11	20	ns
t _{PLH}	Propagation delay time, low-to-high-level output		13	20	ns
t _{PHL}	Propagation delay time, high-to-low-level output		9	15	ns
t _{TLH}	Transition time, low-to-high-level output		4	20	ns
t _{THL}	Transition time, high-to-low-level output		4	20	ns
t _{PZH}	Output enable time to high level		7	20	ns
t _{PZL}	Output enable time to low level		14	40	ns
t _{PHZ}	Output disable time from high level		10	30	ns
t _{PLZ}	Output disable time from low level		17	35	ns
Overshoot factor	$R_L = 100\ \Omega$, See Figure 2, Termination C			10%	

† All typical values are at $T_A = 25^\circ\text{C}$.

SYMBOL EQUIVALENTS

DATA-SHEET PARAMETER	EIA/TIA-422-B
V_O	V_{oa}, V_{ob}
$ V_{OD1} $	V_o
$ V_{OD2} $	V_t
$\Delta V_{OD} $	$ V_t - \bar{V}_t $
V_{OC}	$ V_{os} $
$\Delta V_{OC} $	$ V_{os} - \bar{V}_{os} $
I_{OS}	$ I_{sa} , I_{sb} $
I_O	$ I_{xa} , I_{xb} $

PARAMETER MEASUREMENT INFORMATION

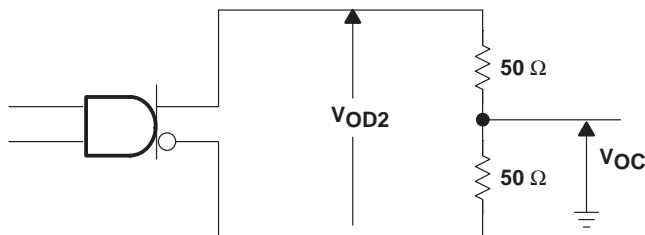
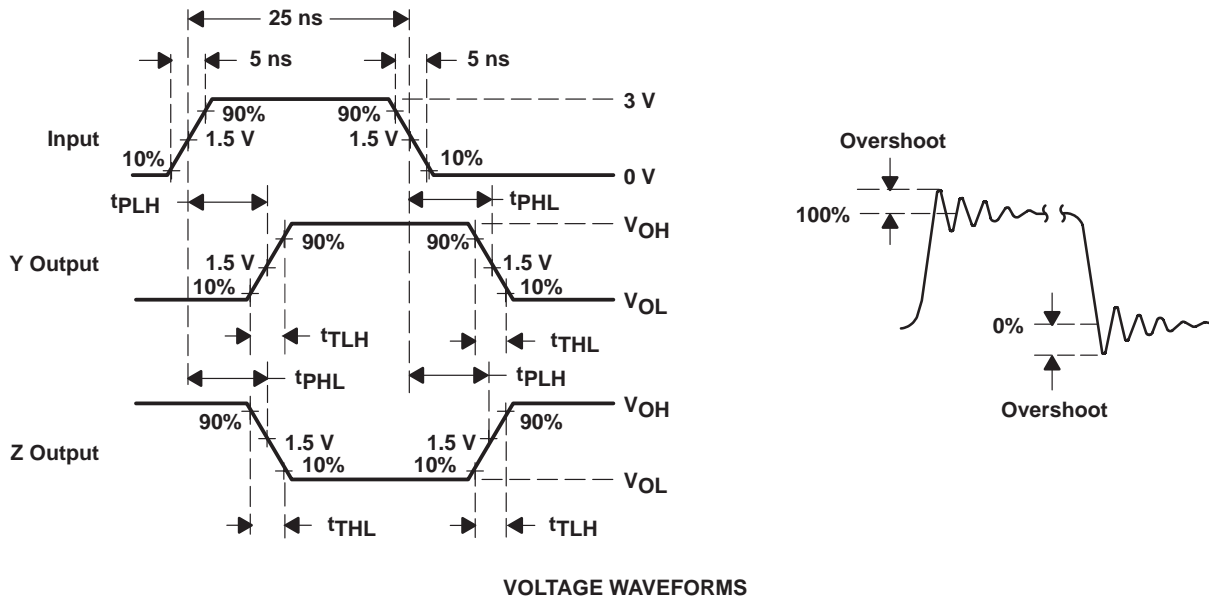
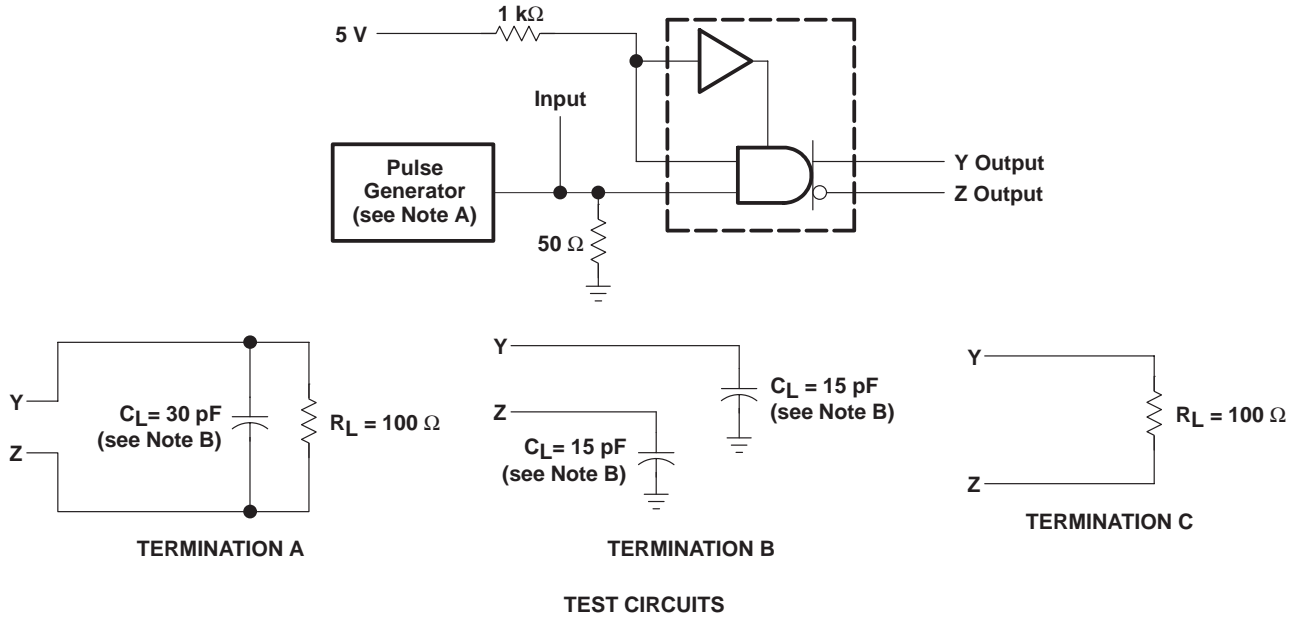


Figure 1. Differential and Common-Mode Output Voltages

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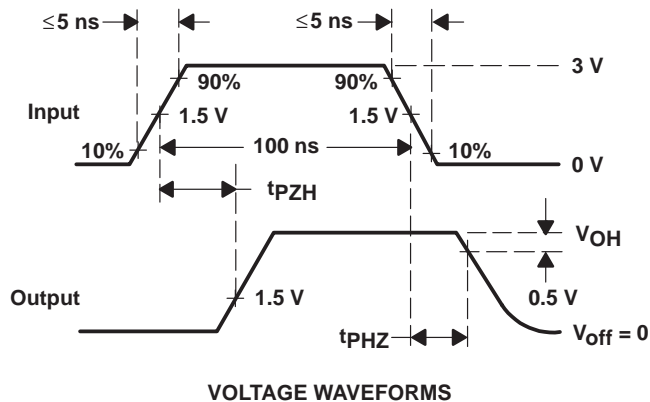
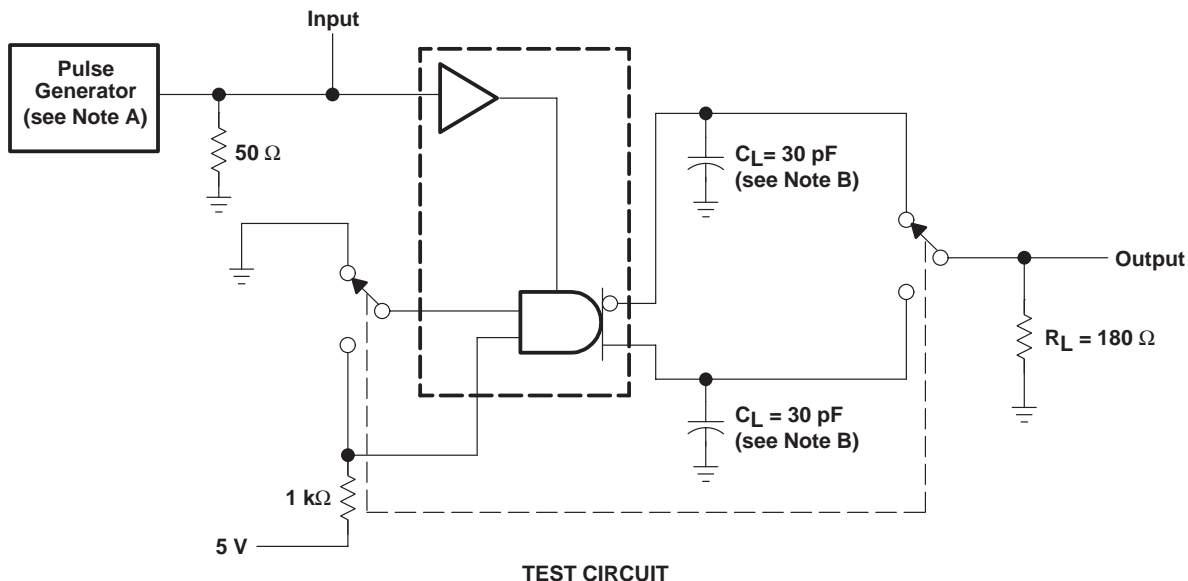
PARAMETER MEASUREMENT INFORMATION



- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, $PRR \leq 10 \text{ MHz}$.
 B. C_L includes probe and jig capacitance.

Figure 2. Test Circuits, Voltage Waveforms, and Overshoot Factor

PARAMETER MEASUREMENT INFORMATION



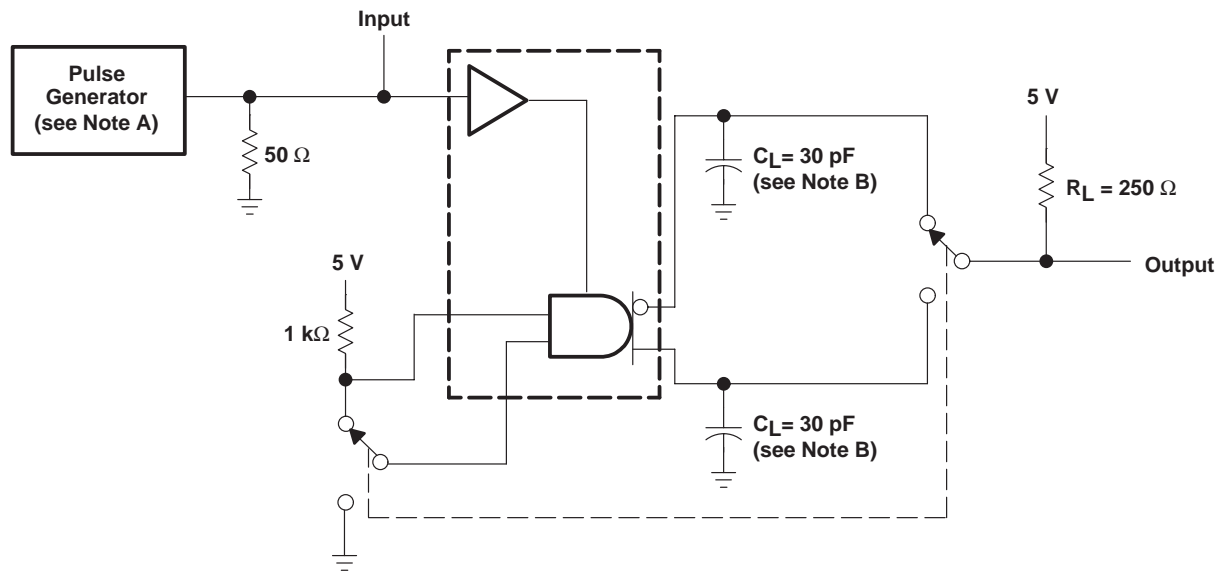
- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$.
 B. C_L includes probe and jig capacitance.

Figure 3. Test Circuit and Voltage Waveforms

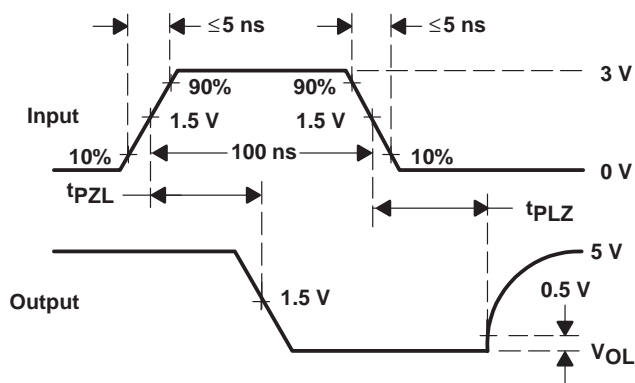
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PARAMETER MEASUREMENT INFORMATION



TEST CIRCUIT



VOLTAGE WAVEFORMS

- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, $PRR \leq 500 \text{ kHz}$.
 B. C_L includes probe and jig capacitance.

Figure 4. Test Circuit and Voltage Waveform

TYPICAL CHARACTERISTICS

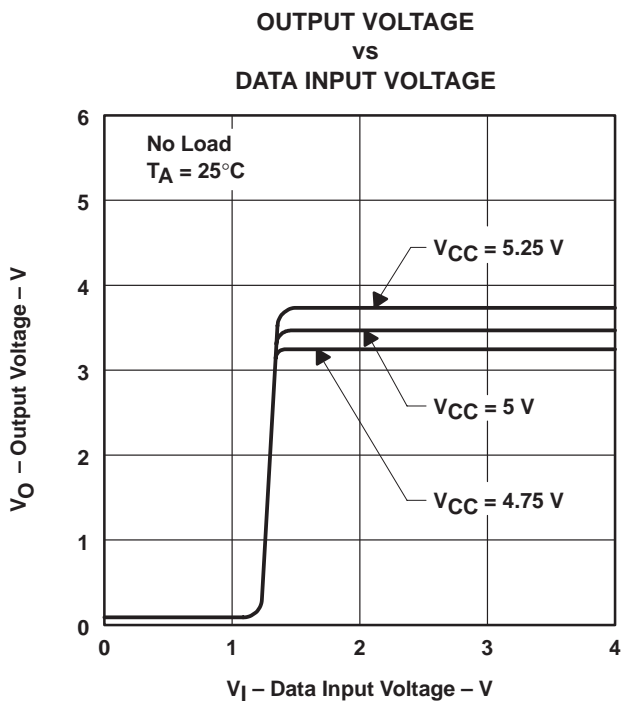


Figure 5

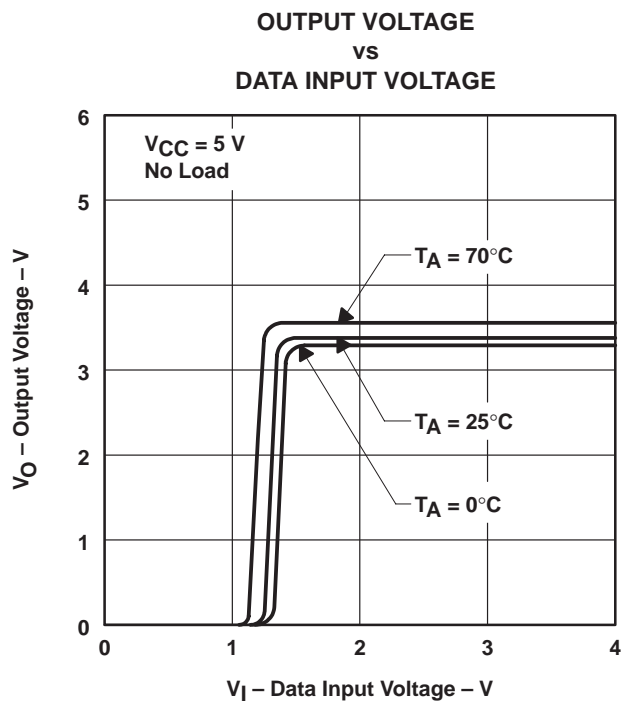


Figure 6

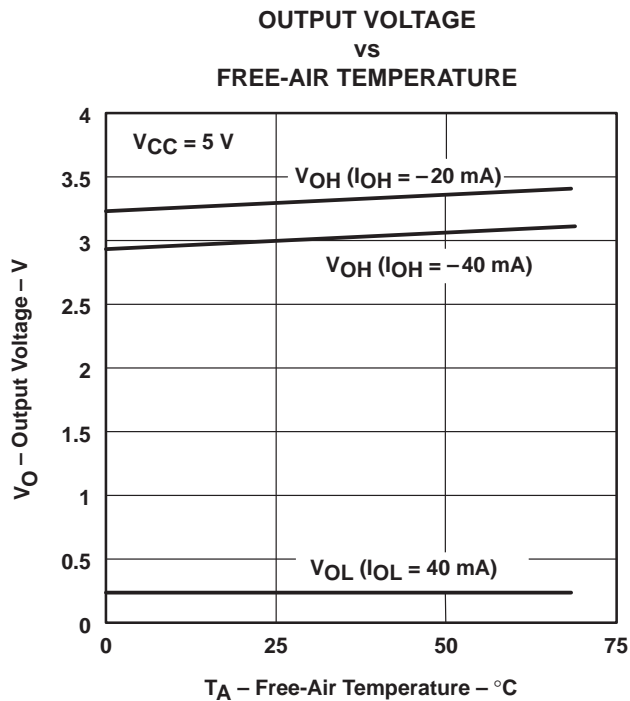


Figure 7

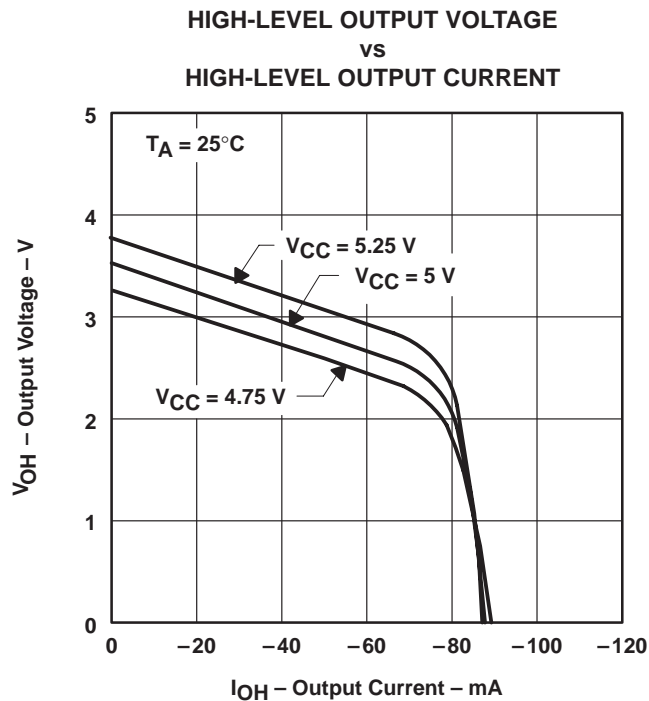


Figure 8

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TYPICAL CHARACTERISTICS

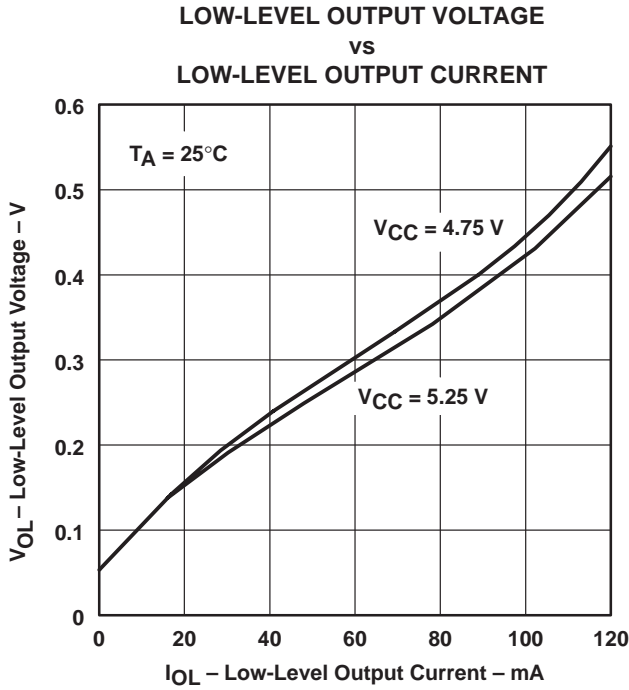


Figure 9

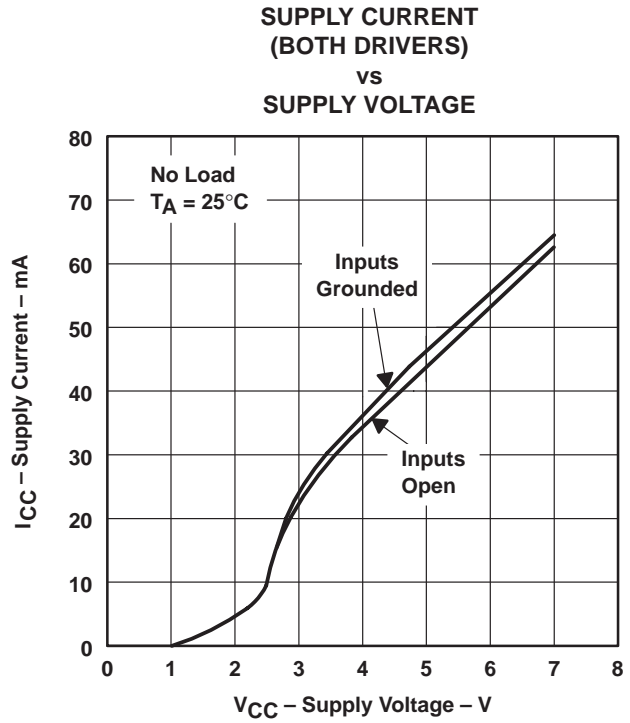


Figure 10

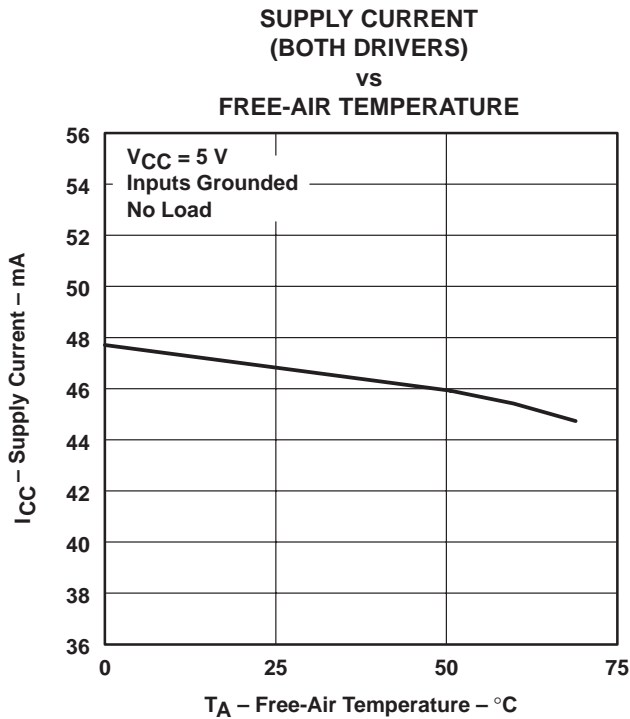


Figure 11

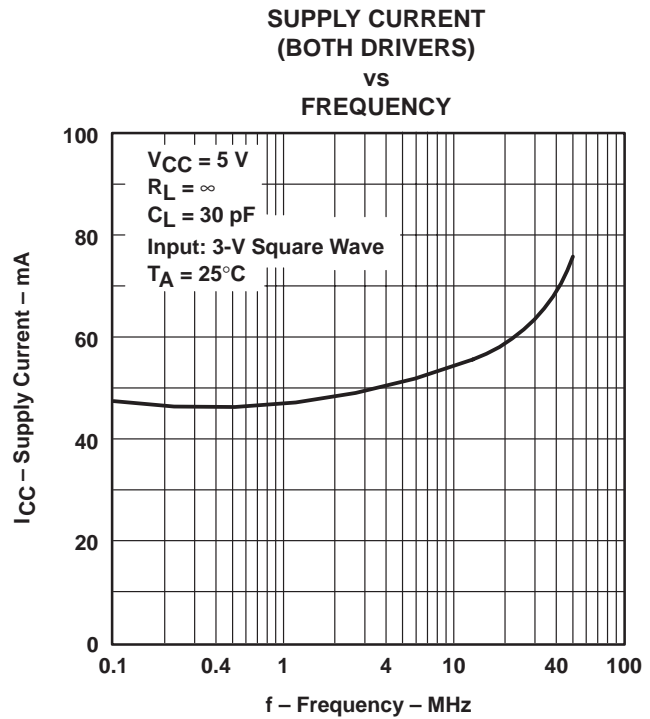


Figure 12



TYPICAL CHARACTERISTICS

PROPAGATION DELAY TIME
 FROM DATA INPUTS
 vs
 FREE-AIR TEMPERATURE

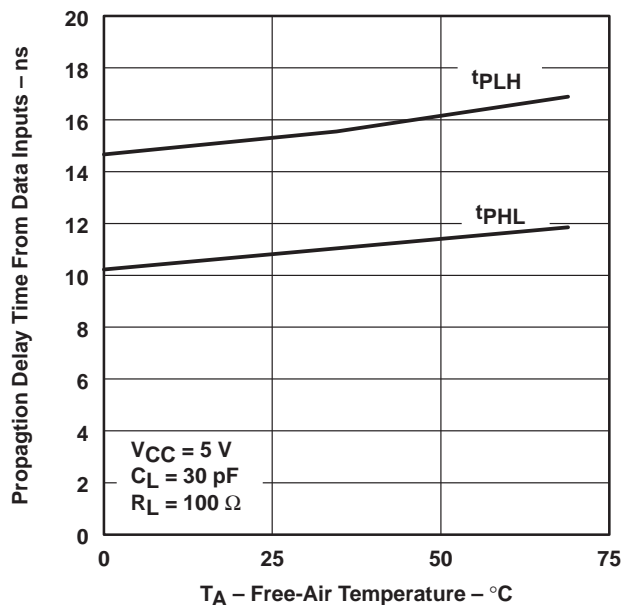


Figure 13

OUTPUT ENABLE AND DISABLE TIME
 vs
 FREE-AIR TEMPERATURE

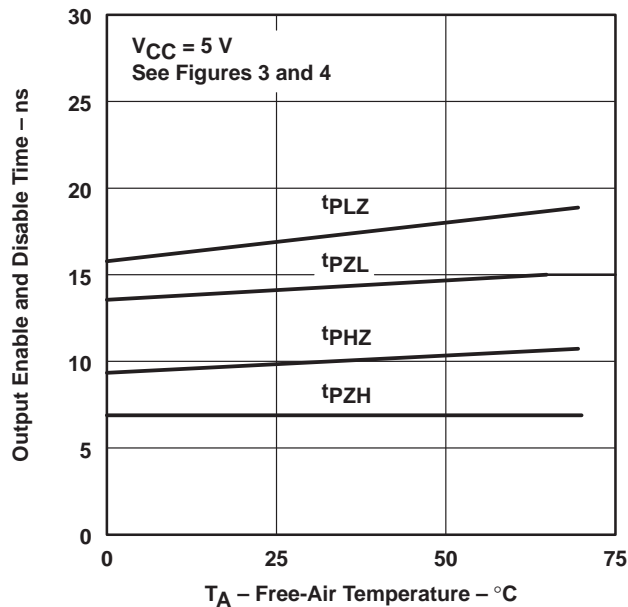


Figure 14

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